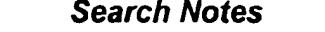


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/674,177	HAN ET AL.
	<b>Examiner</b>	Art Unit
	VanThu Nguyen	2824

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Same as above	above	11/21/65	VTN